Notice of References Cited Application/Control No. 10/747,925 Examiner Walter L. Lindsay, Jr. Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0258145	11-2006	Lee et al.	438/618
*	В	US-2006/0006410	01-2006	Lee et al.	257/145
*	С	US-2005/0239279	10-2005	Park et al.	438/618
*	D	US-2005/0199920	09-2005	Lee et al.	257/288
*	Ε	US-2004/0188745	09-2004	Kim et al.	257/306
*	F	US-2004/0021225	02-2004	Park et al.	257/758
	G	US-			
	Н	US-			
	1	US-	•		
	7	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	·				
	0					
	Р					
	Q					
	R				i.	
	s					
	Т				0	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
•	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.